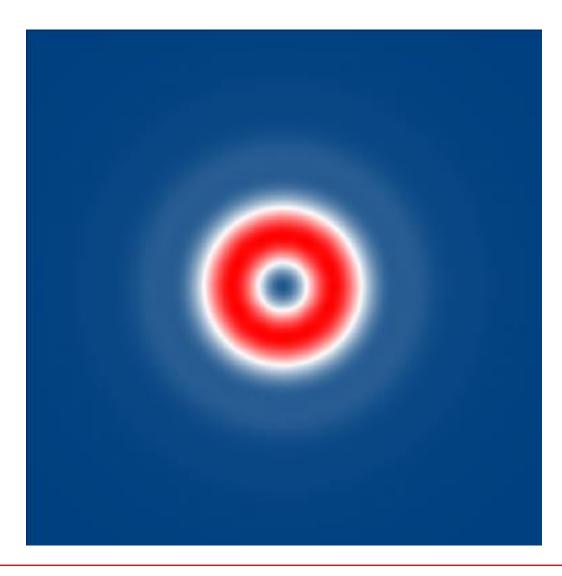


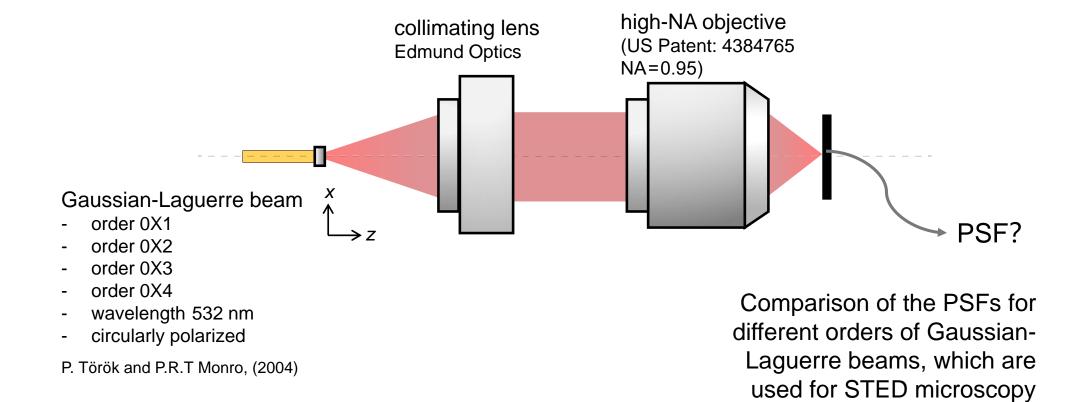
Focusing of Gaussian-Laguerre Beam for STED Microscopy

Abstract



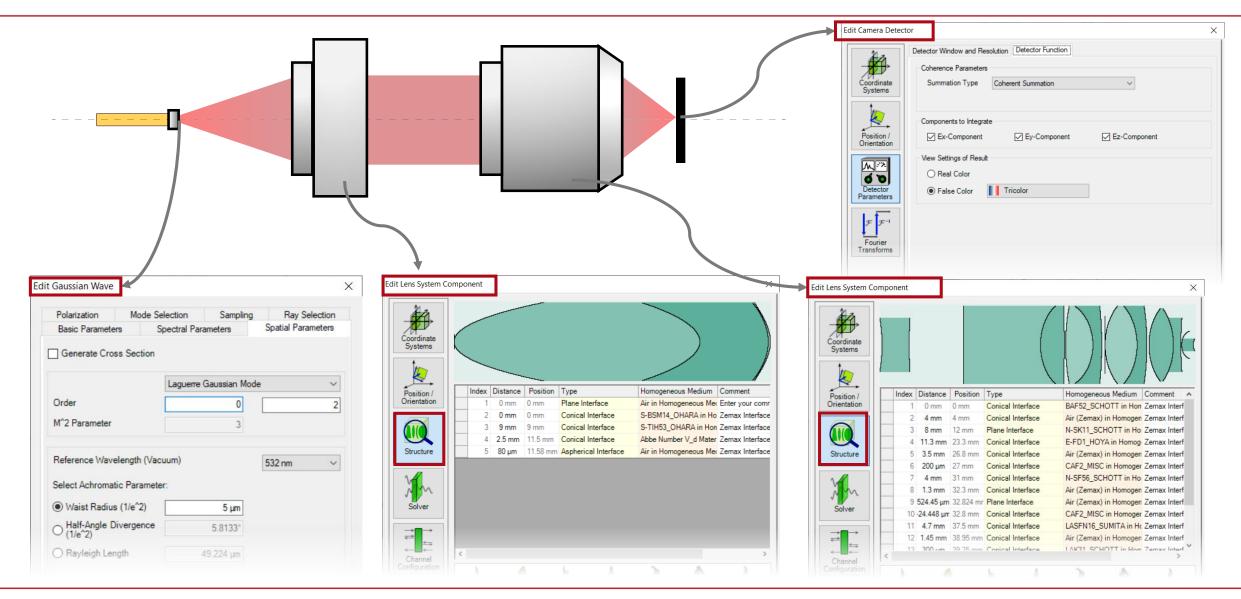
STimulated Emission Depletion (STED) microscopy uses a tiny spot in the focal plane to generate super resolution. Two focused beams are needed. One is the excitation beam. The other one is the depletion beam, which can eliminate the emission light. The depletion beam needs to be donut-shaped. In [P. Török and P.R.T Monro, (2004)], the authors investigated the donut-shaped PSF can be generated by focusing high order Gaussian-Laguerre beam. In VirtualLab Fusion, the focusing of such high-order Gaussian-Laguerre beam is modeled and analyzed straightforwardly.

Scenario

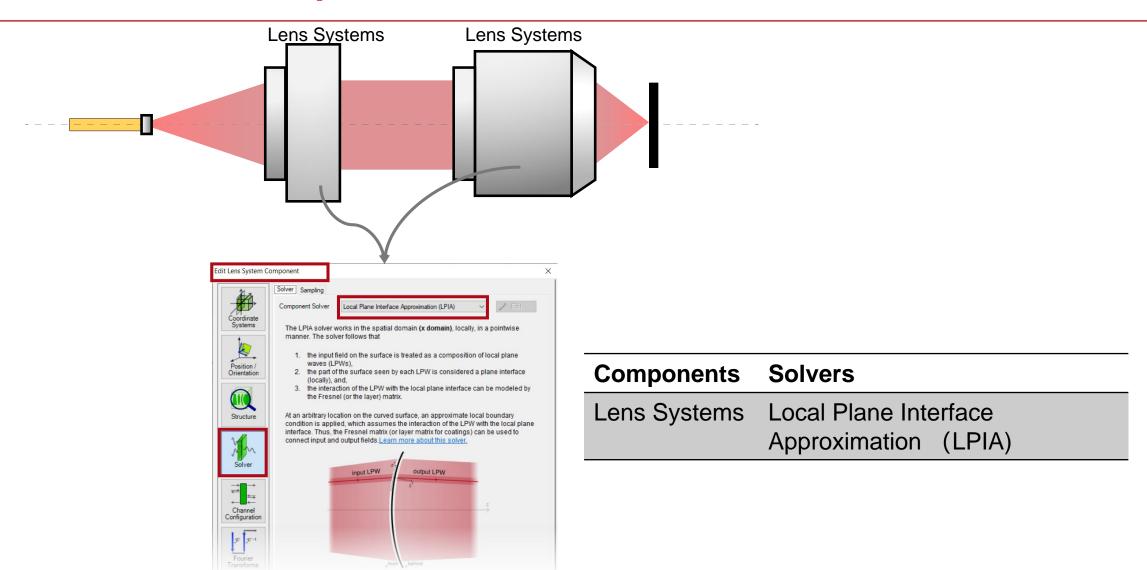


Building the System in VirtualLab Fusion

System Building Blocks



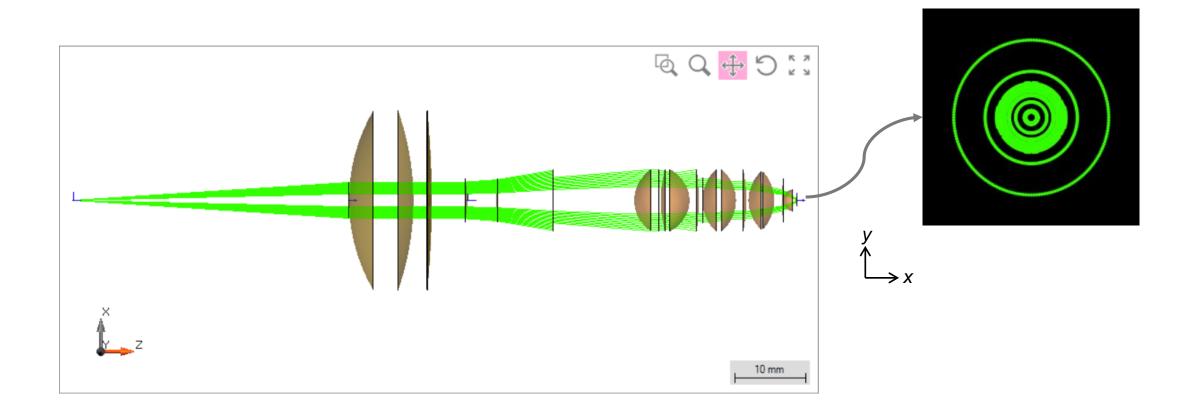
Solvers for Components



Geometric-Optics Simulations

by Ray Tracing

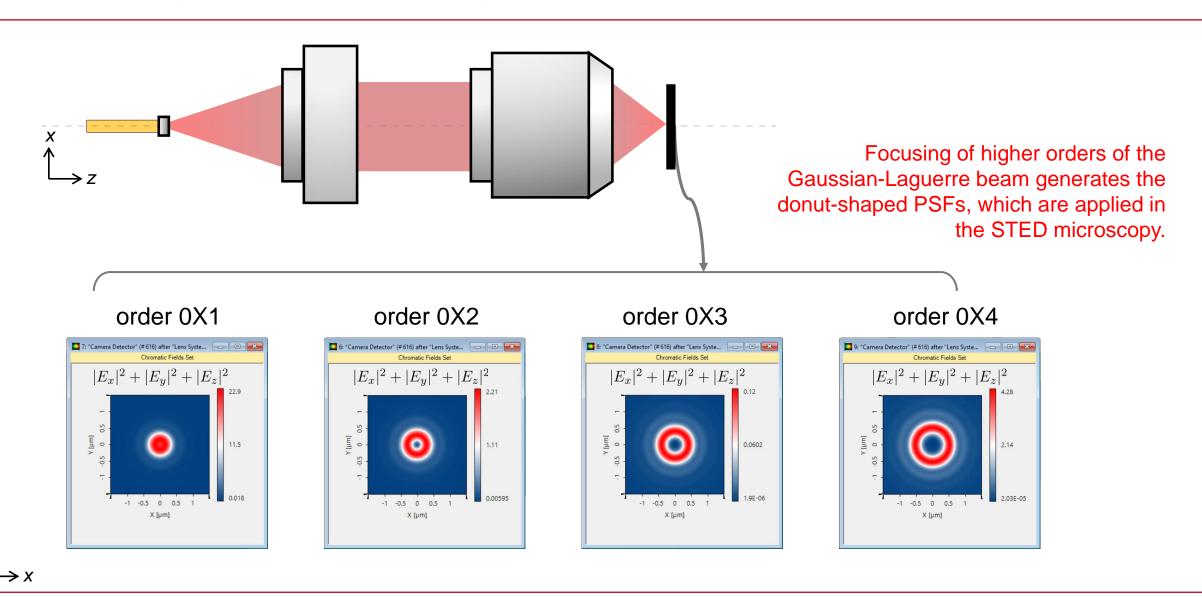
Results: Ray Tracing



Fast Physical-Optics Simulations

by Field Tracing

Focusing of Gaussian-Laguerre Beams



Document Information

title	Focusing of Gaussian-Laguerre Beam for STED Microscopy
document code	MIC.0014
version	1.0
edition	VirtualLab Fusion Basic
software version	2020.2 (Build 1.116)
category	Application Use Case
further reading	 Debye-Wolf Integral Calculator Analyzing High-NA Objective Lens Resolution Investigation for Microscope Objective Lenses by Rayleigh Criterion